

### **Amendments To Claims:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

### **Listing of Claims:**

1. (Currently Amended).     An apparatus for cleaning and shaping a probe tip comprising:  
a support structure having a surface; and  
a pad formed on said surface of said support structure, wherein said pad comprises an adhesive and a plurality of abrasive particles in contact with said adhesive, and wherein said pad is configured for cleaning and shaping a probe tip.
2. (Original).   The apparatus of claim 1 wherein said adhesive is located in an adhesive layer.
3. (Original).   The apparatus of claim 1 wherein said plurality of abrasive particles is located in an abrasive layer.
4. (Original).   The apparatus of claim 1 wherein said adhesive is located in an adhesive layer and wherein said plurality of abrasive particles is located in an abrasive layer.
5. (Currently Amended).     An apparatus for cleaning and shaping a probe tip comprising:  
a support structure having a surface; and  
a pad formed on said surface of said support structure, wherein said pad comprises an adhesive and a plurality of abrasive particles in contact with said adhesive;  
wherein said adhesive is located in an adhesive layer and wherein said plurality of abrasive particles is located in an abrasive layer; and,  
~~The apparatus of claim 4~~ wherein said pad further comprises a plurality of alternating layers of said adhesive layer and said abrasive layer.
6. (Original).   The apparatus of claim 5 wherein at least one of said abrasive layers comprises abrasive particles of a different size than the abrasive particles of another abrasive layer.

7. (Original). The apparatus of claim 6 wherein the size of the abrasive particles increases for each abrasive layer that is further from the support structure.
8. (Currently Amended). An apparatus for cleaning and shaping a probe tip comprising:  
a support structure having a surface;  
a pad formed on said surface of said support structure, wherein said pad  
comprises an adhesive and a plurality of abrasive particles in contact with  
said adhesive; and  
~~The apparatus of claim 1 further comprising~~ a composite layer comprising said  
adhesive and said plurality of abrasive particles.
9. (Original). The apparatus of claim 8 further comprising a plurality of said composite layers.
10. (Original). The apparatus of claim 9 wherein at least one of said composite layers comprises abrasive particles of a different size than the abrasive particles of another composite layer.
11. (Original). The apparatus of claim 10 wherein the size of said abrasive particles increases for each composite layer that is further from the support structure.
12. (Original). The apparatus of claim 9 wherein at least one of said composite layers comprises abrasive particles of a different material than the abrasive particles of another composite layer.
13. (Currently Amended). An apparatus for cleaning and shaping a probe tip comprising:  
a support structure having a surface; and  
a pad formed on said surface of said support structure, wherein said pad  
comprises an adhesive and a plurality of abrasive particles in contact with  
said adhesive;  
~~The apparatus of claim 1 wherein the size of the abrasive particles is between 0.01~~  
microns and 90 microns.

14. (Currently Amended). An apparatus for cleaning and shaping a probe tip comprising:  
a support structure having a surface; and  
a pad formed on said surface of said support structure, wherein said pad  
comprises an adhesive and a plurality of abrasive particles in contact with  
said adhesive;  
~~The apparatus of claim 1~~ wherein the support structure is a semiconductor wafer,  
wherein the adhesive is an acrylic adhesive, and wherein the abrasive  
particles are diamond particles.
15. (Original). A method for cleaning and shaping a probe tip comprising the steps of:  
inserting the probe tip into a multi-layered adhesive and abrasive particle pad; and  
extracting the probe tip.
16. (Original). The method of claim 15 wherein the step of inserting the probe tip comprises  
inserting the probe tip a predetermined distance into the pad, wherein said predetermined  
distance is a function of tip length and pad thickness.
17. (Original). The method of claim 15 wherein the steps of inserting and extracting are  
performed on-line.
18. (Original). The method of claim 15 wherein in the inserting step said multi-layer adhesive  
and abrasive pad comprises abrasive layers, wherein at least one of said abrasive layers  
has abrasive particles having a different size than the abrasive particles of at least one  
other abrasive layer.
19. (Original). The method of claim 15 wherein in the inserting step, said multi-layer adhesive  
and abrasive pad comprises a plurality of composite layers, wherein at least one of said  
composite layers has abrasive particles having a different size than the abrasive particles  
of at least one other composite layer.

20. (Currently Amended). A method of making a probe tip cleaning and shaping pad comprising the steps of:

applying an adhesive layer to a support structure, and  
applying a plurality of abrasive particles to said adhesive layer to form an  
abrasive particle layer, wherein said adhesive layer and said abrasive  
particle layer comprise a probe tip cleaning and shaping pad.

21. (Currently Amended). A method of making a probe tip cleaning and shaping pad  
comprising the steps of:

applying an adhesive layer to a support structure;  
applying a plurality of abrasive particles to said adhesive layer to form an  
abrasive particle layer; and,

~~The method of claim 20 further comprising the steps of:~~

heating the support structure,  
wherein the step of applying ~~an~~ said adhesive layer further comprises rolling the  
adhesive layer with a rolling tool to remove air bubbles; and  
wherein the step of applying the plurality of abrasive particles comprises brushing  
the plurality of abrasive particles on to said adhesive layer.

22. (Currently Amended). A method of making a probe tip cleaning and shaping pad  
comprising the steps of:

applying an adhesive layer to a support structure;  
applying a plurality of abrasive particles to said adhesive layer to form an  
abrasive particle layer; and,

~~The method of claim 20 further comprising the steps of:~~

heating the support structure,  
wherein the step of applying an adhesive layer further comprises placing the  
adhesive layer on the support structure and rolling over the adhesive layer  
with a rolling tool to remove air bubbles; and  
wherein the step of applying the plurality of abrasive particles comprises brushing

the plurality of abrasive particles on to said adhesive layer.

23. (Original). The method of claim 21 wherein in the step of applying the plurality of abrasive particles, said plurality of abrasive particles comprises varying grit sizes for different layers; and wherein said abrasive particles comprise diamond particles.
24. (Original). The method of claim 23 wherein the step of applying the plurality of abrasive particles further comprises graduating the size of the abrasive particles from smallest to largest with increasing distance of layers from the support structure.
25. (Original). The method of claim 24 wherein the step of applying the adhesive layer further comprises using an adhesive backing layer that can be peeled off, leaving the adhesive behind.